

**Notice of References Cited**

Application/Control No.

10/525,296

Applicant(s)/Patent Under  
Reexamination  
UNO ET AL.

Examiner

ANNA L. VERDERAME

Art Unit

1795

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,768,710	07-2004	Kitaura et al.	369/100
*	B	US-5,555,537	09-1996	Imaino et al.	369/94
*	C	US-6,221,455	04-2001	Yasuda et al.	428/64.1
*	D	US-2002/0036979	03-2002	Hayashida et al.	369/286
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	K. Nishiuchi, H. Kitaura, N. Yamada, and N. Akahira. Japanese Journal of Applied Physics. 37(1998) 2163.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.